

# Search Notes



Application No.

10/083,877

Examiner

David C. Meyer

Applicant(s)

WONG ET AL.

Art Unit

2878

## SEARCHED

Class	Subclass	Date	Examiner
250	237R	10/21-10/22	DCM
	341.8		
	306		
	307		
	559.3		
356	399		
	495		
	503		
	625		
	684		
	635		
	630		
	640	V	

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Thanh Luu 250/ 237R, 559.3 text search scatterometry reflectometry ellipsometry	10/7/03	DCM
Richard Rosenberger 356/ 614, 616, 620 text search critical dimension scatterometry, ellipsometry, etc.	9/3/03	DCM

**Search Notes (continued)**



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Class	Subclass	Date	Examiner
356	614	9/3/03	DCM
	616		
	620		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR